For Immediate Release
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Microscopy Society of America Announces Class of 2017 Fellows

Eight to be inducted at 75th anniversary meeting in St. Louis, Missouri.

RESTON, Virginia – Feb. 17, 2017 – The Microscopy Society of America (MSA) announced today its Class of 2017 Fellows. Eight members of the Society will be conferred the honor on August 7 in St. Louis at Microscopy & Microanalysis 2017, which will be the 75th anniversary meeting of MSA. The MSA Fellow designation annually recognizes senior distinguished members of the Society who have made significant contributions to the advancement of the field of microscopy and microanalysis through a combination of scientific achievement and service to the scientific community.

The Class of 2017 Fellows are: **David C. Bell**, *Harvard University*; **Paul E. Fischione**, *E. A. Fischione Instruments, Inc.*; **Christopher J. Kiely**, *Lehigh University*; **Jeanette Killius**, *Northeastern Ohio Medical University*; **Laurence D. Marks**, *Northwestern University*; **Peter Rez**, *Arizona State University*; **Phillip E. Russell**, *Appalachian State University*; and **Heide Schatten**, *University of Missouri – Columbia*. “The Microscopy Society of America prides itself on recognizing the many ways that different individuals contribute to the field, and the Class of 2017 Fellows is exemplary of this diversity,” said Ian M. Anderson, MSA President. “Members of the Class of 2017 represent the gamut of the Society’s mission: scientists whose research activities have furthered our fundamental understanding of a variety of microscopy techniques and their application to diverse scientific studies; technologists who have overseen the practical implementation of these techniques; instrument manufacturers whose developments have opened new avenues for microscopy to impact scientific advancement; and educators whose books have informed and trained those entering the field.”

The Microscopy Society of America was founded as the Electron Microscope Society of America in 1942, a time of rapid development for an instrument that promised, for the first time, better resolving power than that (of the order of one micrometer) of the traditional light microscope. The Society adopted its current name on the occasion of its 50th anniversary, to reflect the diversity of microscopy techniques represented by its membership. Today, a variety of microscopes are capable of imaging individual atoms, and providing chemical information to identify what kind of atom is being imaged, while a variety of microscopes of lower resolving

power continue to play an enabling role in understanding the world around us at a microscopic scale, and the development of new technologies. As it celebrates its 75th anniversary this year, the Microscopy Society of America champions all forms of microscopy through its annual meeting, its publications, and its educational outreach.

Microscopy & Microanalysis (M&M) is the annual meeting of the Microscopy Society of America and the Microanalysis Society (MAS). M&M 2017, to be held August 6-10 in St. Louis, Missouri, will be cosponsored for the first time by the International Field Emission Society (IFES). M&M 2017 marks significant anniversaries for all three societies: the 75th anniversary of MSA, the 50th anniversary of MAS, and the 50th anniversary of the invention of the atom probe field ion microscope, an instrument based on high-field science, the scientific emphasis of IFES.

The Microscopy Society of America is an affiliate society of the American Institute of Physics (AIP) and the American Association for the Advancement of Science (AAAS).

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For promotional purposes, photographs of individual Fellows and their citations can be found on the MSA web site:
http://www.microscopy.org/awards/listoffellows.cfm

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